CD74HCU04

Data sheet acquired from Harris Semiconductor
SCHS127

February 1998

High Speed CMOS Logic Hex Inverter

Features

- **Typical Propagation Delay: 6ns at V_{CC} = 5V, C_L = 15pF, T_A = 25^oC, Fastest Part in QMOS Line**
- **Wide Operating Temperature Range . . . -55^oC to 125^oC**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HCU Types**
  - **2V to 6V Operation**
  - **High Noise Immunity: N_{IL} = 20%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V**
- **CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}**

Description

The Harris CD74HCU04 unbuffered hex inverter utilizes silicon-gate CMOS technology to achieve operation speeds similar to LSTTL gates with the low power consumption of standard CMOS integrated circuits. These devices are especially useful in crystal oscillator and analog applications. Figures 10 and 11 are supplied as design information for the above applications.

Ordering Information

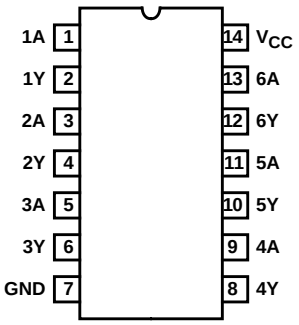
PART NUMBER	TEMP. RANGE (^oC)	PACKAGE	PKG. NO.
CD74HCU04E	-55 to 125	14 Ld PDIP	E14.3
CD74HCU04M	-55 to 125	14 Ld SOIC	M14.15

NOTES:

1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer or die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Pinout

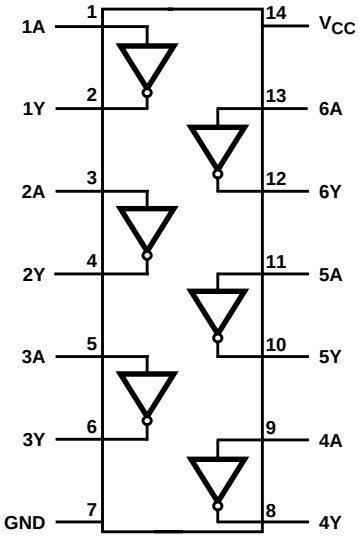
CD74HC04,
(PDIP, SOIC)
TOP VIEW



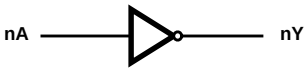
CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

File Number **1655.1**

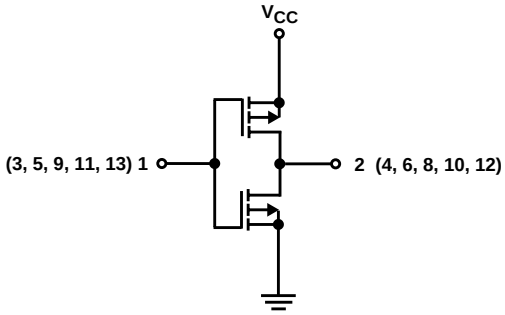
Functional Diagram



Logic Symbol



Schematic Diagram



Absolute Maximum Ratings

DC Supply Voltage, V_{CC}
Voltages Referenced to Ground . . . . . -0.5V to +7V
DC Input Diode Current, I_{IK}
For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . . ±20mA
DC Drain Current, per Output, I_O
For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . . ±50mA

Operating Conditions

Temperature Range T_A . . . . . -55°C to 125°C
Supply Voltage Range, V_{CC} . . . . . 2V to 6V
DC Input or Output Voltage, V_I, V_O . . . . . 0V to V_{CC}
Input Rise and Fall Time
2V . . . . . 1000ns (Max)
4.5V. . . . . 500ns (Max)
6V . . . . . 400ns (Max)

Thermal Information

Thermal Resistance (Typical, Note 3)	θ_{JA} (°C/W)
PDIP Package	100
SOIC Package	180

Maximum Junction Temperature (Hermetic Package or Die) . . . 175°C
Maximum Junction Temperature (Plastic Package) . . . . . 150°C
Maximum Storage Temperature Range . . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . . 300°C
(SOIC - Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C		-40°C TO +85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
High Level Input Voltage	V_{IH}	-	-	2	1.7	-	1.7	-	1.7	-	V
				4.5	3.6	-	3.6	-	3.6	-	V
				6	4.8	-	4.8	-	4.8	-	V
Low Level Input Voltage	V_{IL}	-	-	2	-	0.3	-	0.3	-	0.3	V
				4.5	-	0.8	-	0.8	-	0.8	V
				6	-	1.1	-	1.1	-	1.1	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.8	-	1.8	-	1.8	-	V
			-0.02	4.5	4	-	4	-	4	-	V
			-0.02	6	5.5	-	5.5	-	5.5	-	V
High Level Output Voltage TTL Loads		V_{CC} or GND	-4	4.5	3.98	-	3.84	-	3.7	-	V
			-5.2	6	5.48	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	0.2	-	0.2	-	0.2	V
			0.02	4.5	-	0.5	-	0.5	-	0.5	V
			0.02	6	-	0.5	-	0.5	-	0.5	V
Low Level Output Voltage TTL Loads			4	4.5	-	0.26	-	0.33	-	0.4	V
		V_{CC} or GND	5.2	6	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	2	-	20	-	40	µA

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Propagation Delay, Input to Output Y (Figure 1)	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	70	-	90	-	105	ns
		C_L = 50pF	4.5	-	-	14	-	18	-	21	ns
		C_L = 15pF	5	-	5	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	12	-	15	-	18	ns
Transition Times (Figure 1)	t_{TLH}, t_{THL}	C_L = 50pF	2	-	-	75	-	95	18	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	C_I	-	See Figure 3								pF
Power Dissipation Capacitance (Notes 4, 5)	C_{PD}	-	5	-	14	-	-	-	-	-	pF

NOTES:

4. C_{PD} is used to determine the dynamic power consumption, per inverter.
5. $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.

Test Circuits and Waveforms

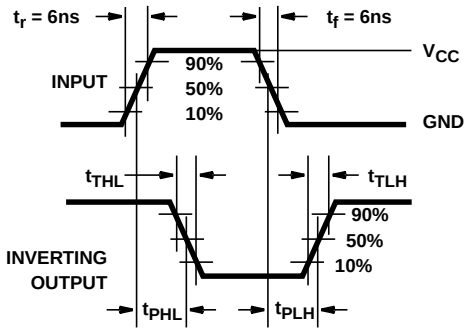


FIGURE 1. HC AND HCU TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

Typical Performance Curves

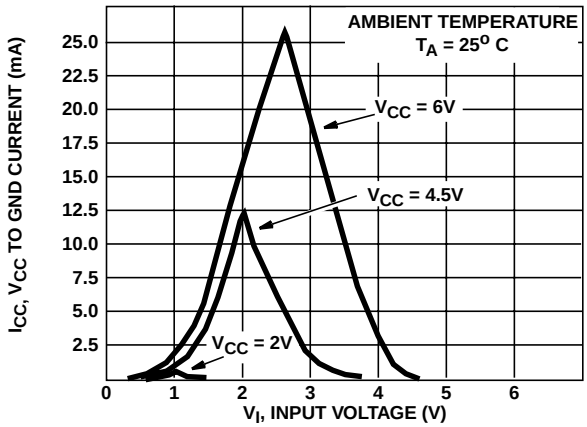


FIGURE 2. TYPICAL INVERTER SUPPLY CURRENT AS FUNCTION OF INPUT VOLTAGE

Typical Performance Curves (Continued)

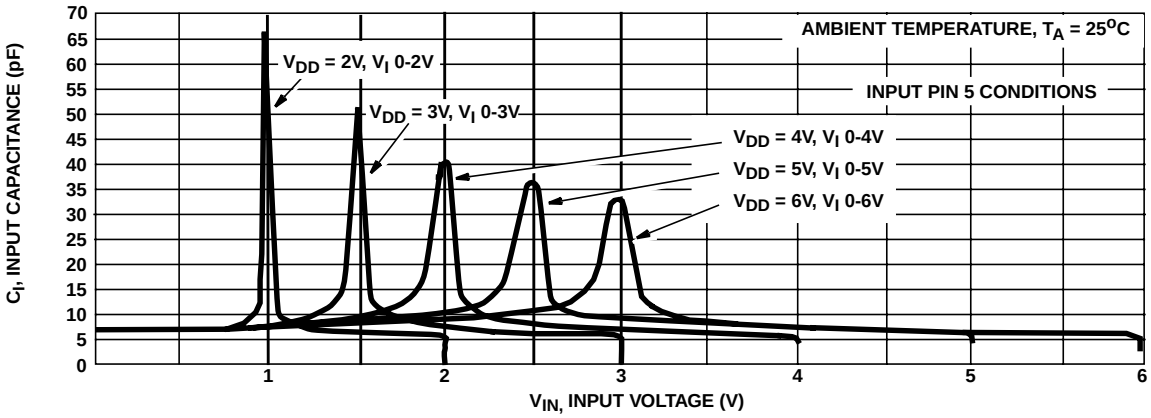


FIGURE 3. INPUT CAPACITNCE AS A FUNCTION OF INPUT VOLTAGE

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